Zernike used in semiconductor wafer aberratio Search

more » Froogle Local Groups News Web Images

Advanced Search Preferences

Web

Results 21 - 30 of about 114 for zernike used in semiconductor wafer aberration measurement. (0.15 seconds)

SPIE Proceedings Vol. 2778

www.spie.org/web/abstracts/2700/2778.html - 43k - Supplemental Result - Cached - Similar pages ... Method of the System Error Used for CCD MTF ... of a Ray-Detector for Examination of Semiconductor Devices in ... Generalization of the Van Cittert-Zernike Theorem to More results from www.spie.org

Por Wet-Etch Figuring: Optical Surfacing by Controlled Application of ...

File Format: PDF/Adobe Acrobat - View as HTML

... the semiconductor processing industry for critical wafer drying applications.

www.llnl.gov/nif/lst/diffractive-optics/ UCRL-JC-143914-spie_V4451.pdf - Similar pages ... Interferometric measurements. were taken along one line, and used to ...

гръг <u>Tanya E</u> File Format: PDF/Adobe Acrobat - <u>View as HTML</u>

Measurement of solar constant in near UV and visible wavelengths. Developed a new www.coloradophotonics.org/PDF/Resumes/TonyaJewell.pdf - Similar pages approach describing third order aberration fields of simple tilted and ...

Department of Electrical Engineering

Topics include circuit analysis and simulation, semiconductor device fundamentals and ... Optical materials and properties; third order aberration theory. ... www.ee.utdallas.edu/gradcourse.html - 63k - Cached - Similar pages oe magazine - progress report: 157-nm lithography prepares to graduate An overlay of 23 nm (mean +3 o) on product wafers must be achieved and bettered. ... oemagazine.com/fromTheMagazine/feb03/157.html - 41k - Cached - Similar pages Based on the measurement data obtained from large batches of finished ...

Integrated Circuits for 2003

www.eecs.berkeley.edu/IPRO/ Summary/03abstracts/chapter4.html - 107k - Cached - Similar pages The optimum targets are inverse Fourier transforms of the Zernike polynomials based aberration targets to measure individual Zernike aberration terms.

ppp Initial Results from the EUV Engineering Test Stand

http://www.google.com/search?q=zernike+used+in+semiconductor+wafer+aberration+measurement&hl=en&lr=&start=20&sa=N 8/16/2005

File Format: PDF/Adobe Acrobat - <u>View as HTML</u> **used** as a control to reproduce across-plane focus on subsequent **wafers** as ...

was **used** to measure the separation between the marks. These **measurements** were ...

www.eecs.berkeley.edu/~jbokor/Full_text_pubs/2-177.pdf - <u>Similar pages</u>

feber Preparations for EUV interferometry of the 0.3 NA MET optic File Format: PDF/Adobe Acrobat - View as HTML annular Zernike polynomials yields an RMS wavefront aberration magnitude of 0.56 nm (λ ... used in the measurement of 0.1 NA optics in the past. ...

repositories.cdlib.org/cgi/viewcontent. cgi?article=1452&context=lbnl - <u>Similar pages</u>

PDFI Engineering and Laboratory Notes

File Format: PDF/Adobe Acrobat

semiconductor wafers or chips, by optical polishing their ... other hand the Zernike coefficients obtained by interfero-. metric measurements often cover ... ao.osa.org/ViewMedia.cfm?id=65278&seq=0 - Similar pages [More results from ao.osa.org]

Semiconductor International - Improved Imaging Metrology Needed ...

www.reedelectronicsgroup.com/semiconductor/ article/CA82791?pubdate=4%2F1%2F2001 - Supplemental Result - Similar pages ... The International Technology Roadmap for Semiconductors (ITRS) 1 ... linear sensitivity model can be used has been ... FAMIS measures the Zernike coefficients Z 9 , Z ...

4 G00000000g l e ▶

Result Page: Previous 1 2 3 4 5 6 7 8 9 Next

zernike used in semiconductor wafei Search

Search within results | Language Tools | Search Tips

Google Home - Advertising Programs - Business Solutions - About Google

©2005 Google

http://www.google.com/search?q=zernike+used+in+semiconductor+wafer+aberration+measurement&hl=en&lr=&start=20&sa=N 8/16/2005